

#### Description

The AP3P06Al uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.



 $V_{DS} = -60V I_{D} = -3 A$ 

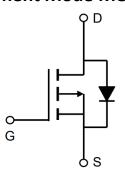
 $R_{DS(ON)}$  < -180m $\Omega$  @  $V_{GS}$ =-10V

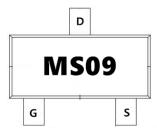
#### **Application**

**Battery protection** 

Load switch

Uninterruptible power supply







**Package Marking and Ordering Information** 

Product ID	Pack	Marking	Qty(PCS)
AP3P06AI	SOT-23	MS09	3000

#### Absolute Maximum Ratings (T<sub>C</sub>=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	-60	V
Vgs	Gate-Source Voltage	±20	V
I <sub>D</sub> @T <sub>A</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup>	-3.3	Α
I <sub>D</sub> @T <sub>A</sub> =70°C	Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup>	-1.4	Α
Іом	Pulsed Drain Current <sup>2</sup>	-7	А
P <sub>D</sub> @T <sub>A</sub> =25°C	Total Power Dissipation <sup>3</sup>	1	W
Тѕтс	Storage Temperature Range	-55 to 150	°C
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C
R <sub>θ</sub> JA	Thermal Resistance Junction-Ambient <sup>1</sup>	125	°CMV
R <sub>θ</sub> JC	Thermal Resistance Junction-Case <sup>1</sup>	80	°CM



#### **Electrical Characteristics (Tc=25℃unless otherwise noted)**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-60			V
△BVɒss/△Tɹ	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25℃ , I <sub>D</sub> =-1mA		-0.021		V/°C
	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-10V , I <sub>D</sub> =-1.5A		130	185	mΩ
Rds(on)		V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-1A		158	200	
V <sub>G</sub> S(th)	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_{D}$ =-250uA	-1.0		-2.5	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	VGS VDS, 1D 200011	-	4.08		mV/℃
lpss	Drain-Source Leakage Current	V <sub>DS</sub> =-48V , V <sub>GS</sub> =0V , T <sub>J</sub> =25℃			1	۸
1055		V <sub>DS</sub> =-48V , V <sub>GS</sub> =0V , T <sub>J</sub> =55℃			5	uA
Igss	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =-5V , I <sub>D</sub> =-1.5A		5.9		S
Qg	Total Gate Charge (-4.5V)	V <sub>DS</sub> =-20V , V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-1.5A		4.6		
Qgs	Gate-Source Charge			1.4		nC
Qgd	Gate-Drain Charge			1.62		
T <sub>d(on)</sub>	Turn-On Delay Time			17.4		
Tr	Rise Time	$V_{DS}$ =-15V , $V_{GS}$ =-10V , $R_{G}$ =3.3		5.4		ns
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =-1A		37.2		115
T <sub>f</sub>	Fall Time			2.4		
Ciss	Input Capacitance			531		
Coss	Output Capacitance	V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , f=1MHz		59		рF
Crss	Reverse Transfer Capacitance			38		
ls	Continuous Source Current <sup>1,4</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-1.7	Α
Isм	Pulsed Source Current <sup>2,4</sup>	v <sub>G</sub> -v <sub>D</sub> -ov , roice Curient			-7	Α
VsD	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25℃			-1.2	V

#### Note:

<sup>1.</sup>The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.

<sup>2.</sup>The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%

<sup>3.</sup>The power dissipation is limited by 150°C junction temperature

<sup>4.</sup> The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



### **Typical Characteristics**

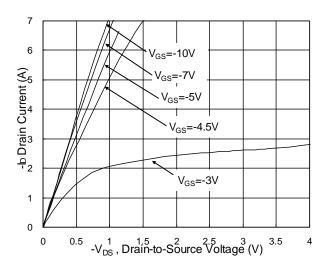


Fig.1 Typical Output Characteristics

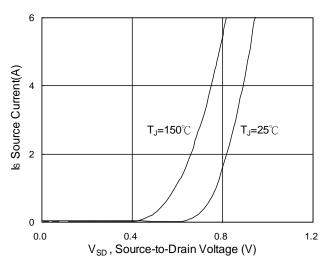


Fig.3 Forward Characteristics Of Reverse

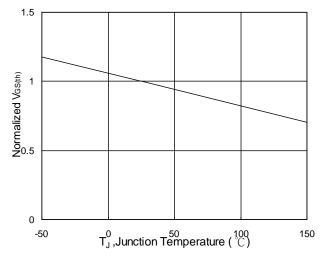


Fig.5 Normalized  $V_{GS(th)}$  v.s  $T_J$ 

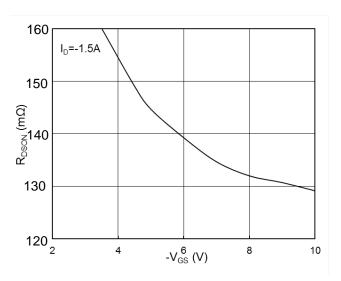
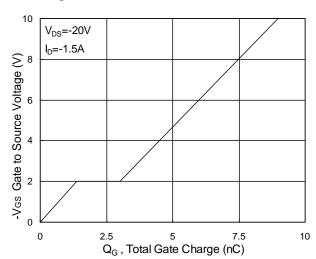


Fig.2 On-Resistance v.s Gate-Source



**Fig.4 Gate-Charge Characteristics** 

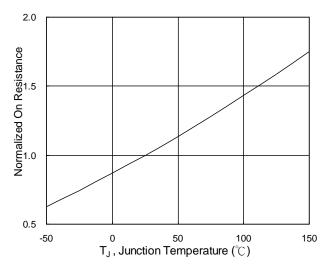
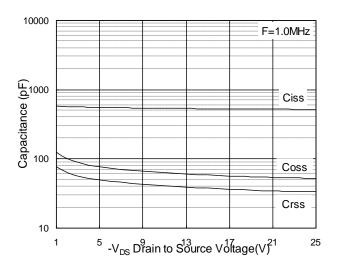


Fig.6 Normalized R<sub>DSON</sub> v.s T<sub>J</sub>







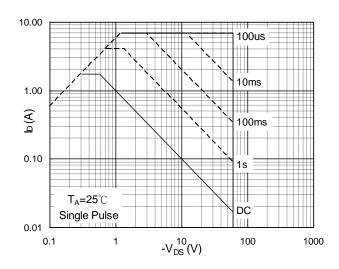


Fig.7 Capacitance

Fig.8 Safe Operating Area

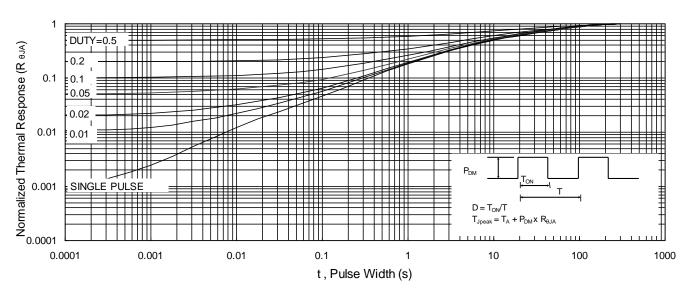


Fig.9 Normalized Maximum Transient Thermal Impedance

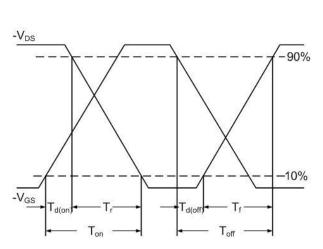


Fig.10 Switching time waveform

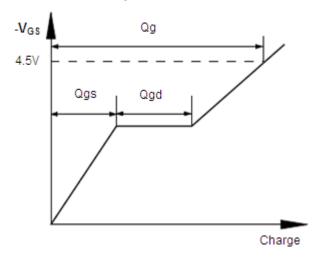
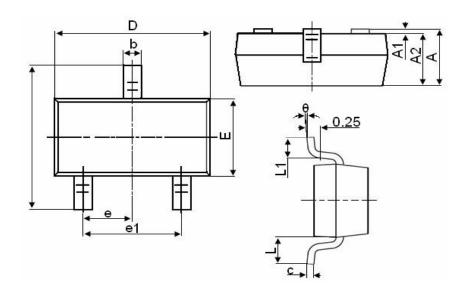


Fig.11 Gate Charge waveform



# Package Mechanical Data-SOT-23



Summa la al	Dimensions in Millimeters		
Symbol	MIN.	MAX.	
А	0.900	1.150	
A1	0.000	0.100	
A2	0.900	1.050	
b	0.300	0.500	
С	0.080	0.150	
D	2.800	3.000	
E	1.200	1.400	
E1	2.250	2.550	
е	0.950TYP		
e1	1.800	2.000	
L	0.550REF		
L1	0.300	0.500	
θ	0°	8°	



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Edition	Date	Change
Rve3.7	2019/4/10	Initial release
Rve3.9	2020/3/25	Reduce RDS(on)

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# Test Report For 30PCS (30pcs 典型測試報告)

